

Notice of References Cited	Application/Control No. 10/085,919	Applicant(s)/Patent Under Reexamination MAYER ET AL.	
	Examiner Cynthia Britt	Art Unit 2133	Page 1 of 1

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	C	US-5,642,363	06-1997	Smith, Gregory James	714/729
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	V	Narayanan, S. and Breuer, M.A.; Reconfiguration techniques for a single scan chain; IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, vol.: 14 Issue: 6, Jun. 1995, Page(s): 750-765.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.